HEWLETT-PACKARD COMPANY
Intellectual Property Administration
P. O. Box 272400
Fort Collins, Colorado 80527-2400

IPW

PATENT APPLICATION

ATTORNEY DOCKET NO. 200207937-1

IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Naysen J. Robertson, et al. **Confirmation No.:** TBA

Application No.: 10/606,714 **Examiner:** To Be Assigned

Filing Date: 06-26-2003 **Group Art Unit:** TBA

Title: Method and Construct For Enabling Programmable, Integrated System Margin Testing

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

(X) under 37 CFR 1.97(b), or
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)

( ) under 37 CFR 1.97 (c) together with either a:
( ) Statement under 37 CFR 1.97(e), or
( ) a $180.00 fee under 37 CFR 1.17(p), or
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)

( ) under 37 CFR 1.97 (d) together with a:
( ) Statement under 37 CFR 1.97(e)(1) or (2), and
( ) a $180.00 fee set forth in 37 CFR 1.17(p).
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account **08-2025** the sum of $0.00 . At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account **08-2025** pursuant to 37 CFR 1.25.

(X) Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Statement together with any required copies of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

(X) A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individuals(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

( ) I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Alexandria, VA 22313-1450. Date of Deposit: _____

OR

( ) I hereby certify that this paper is being transmitted to the Patent and Trademark Office facsimile number _____ on _____
Number of pages:

Typed Name:

Signature: _____

Respectfully submitted,

Naysen J. Robertson, et al.

By _____

Michael G. Verga, Esq.
Attorney/Agent for Applicant(s)
Reg. No. **39,410**

Date: **12-09-2004**

Telephone No.: **(703) 591-2664**

PATENT APPLICATION
Sheet 1 of 1

FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.	APPLICATION NO.	CONFIRMATION NO.
200207937-1	10/606,714	TBA
APPLICANT: Naysen J. Robertson, et al.		
FILING DATE: 06-26-2003	GROUP: TBA	

REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	1A	5,157,326	Oct. 20, 1992	Burnsides	
	1B	6,476,615	Nov. 5, 2002	Marbot et al.	
	1C				
	1D				
	1E				
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L	EP 0 505 120	09-23-1992			
	1M	JP 5-2502	01-08-1993			
	1N					
	1O					
	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	1Q	UK Search Report; Application No. GB0413502.6, November 9, 2004.
	1R	Tsukude, et al. "Highly Reliable Testing of ULSI Memories with On-Chip Voltage-Down Converters". IEEE Design & Test Of Computers. June 1993, pgs. 6-12.
	1S	Berner, et al. "DC Voltage Margin Tester:. NB84092465. IBM Technical Disclosure Bulletin, Vol. 27, No. 4B, September 1984, pg 246.

EXAMINER	DATE CONSIDERED